



### Low-Power 4-Output ZDB / Fanout Clock Buffer for PCle 5.0 and UPI

#### **Features**

- Four Differential Low-Power HCSL Outputs with On-Chip Termination
- Default  $Z_{OUT} = 85\Omega$
- Spread Spectrum Tolerant
- Individual Output Enable
- · Selectable PLL Bandwidths
- Hardware/SMBus Control of ZDB and Fanout Buffer Modes
- 1-400MHz Fanout Buffer Operation
- Differential Output-to-output Skew <50ps
- Very Low Jitter Outputs
  - Differential Cycle-to-cycle Jitter <50ps</li>
  - Fanout Buffer Mode Additive Phase Jitter:
    - PCIe<sup>®</sup> 5.0 CC: 17fs RMS typ
    - DB2000Q Additive Jitter: 28fs RMS typ
    - QPI/UPI 11.4GB/s: 20fs RMS typ
    - IF-UPI Additive Jitter: 60fs RMS typ
  - ZDB Mode Phase litter:
    - PCIe 5.0 CC: 18fs RMS typ
    - QPI/UPI 11.4GB/s: 80fs RMS typ
    - IF-UPI Additive Jitter: 60fs RMS typ
- Core Supply Voltage: 3.3V
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/104/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative.

https://www.diodes.com/quality/product-definitions/

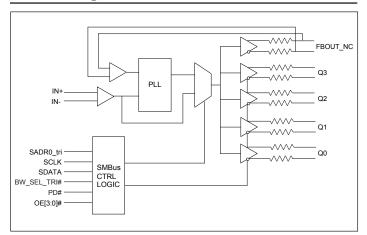
- Packaging (Pb-free & Green):
  - 32-pin, 5mm × 5mm TQFN (ZH)

### **Description**

The DIODES<sup>TM</sup> PI6CBE33045 is a low-power PCIe 1.0/2.0/3.0/4.0/5.0 clock buffer. It takes a reference input to fanout four 100 MHz low-power differential HCSL outputs with on-chip terminations for  $85\Omega$  output impedance. It supports both zero-delay and fanout buffer functions for various applications. An individual OE pin for each output provides easier power management.

It uses Diodes proprietary PLL design to achieve very-low jitter that meets PCIe 1.0/2.0/3.0/4.0/5.0 requirements.

### **Block Diagram**



#### Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

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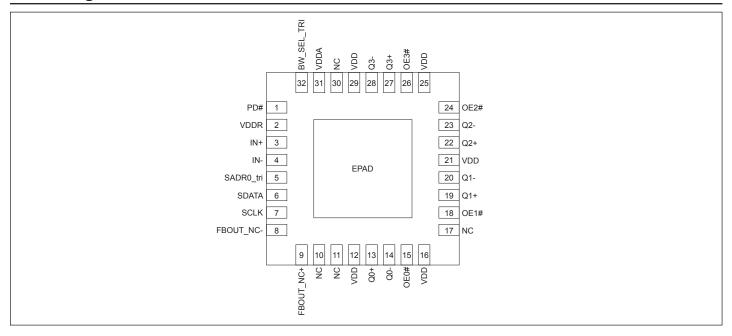
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# **Pin Configuration**



## **Pin Description**

Pin Number	Pin Name	Ту	pe	Description
1	PD#	Input	CMOS	Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode; subsequent high assertions exit Power Down Mode. This pin has internal pullup resistor.
2	VDDR	Power	_	Analog VDD for receiver
3	IN+	Input	HCSL	Differential true clock input
4	IN-	Input	HCSL	Differential complementary clock input
5	SADR0_tri	Input	Tri-level	Latch to select SMBus Address. This pin has an internal pulldown.
6	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
7	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
8	FBOUT_NC-	_	_	Complementary differential feedback output. This pin should NOT be connected to anything outside the chip. It exists to provide delay path matching to get zero propagation delay.
9	FBOUT_NC+	_	_	True differential feedback output. This pin should NOT be connected to anything outside the chip. It exists to provide delay path matching to get zero propagation delay.
10, 11, 17, 30	NC	_	_	Do not connect this pin.
12, 16, 21, 25, 29	$V_{\mathrm{DD}}$	Power	_	Power supply, nominal 3.3V
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output





### **Pin Description Cont.**

Pin Number	Pin Name	Ту	pe	Description
15	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pulldown. $1 = disable$ outputs, $0 = enable$ outputs
18	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pulldown. $1 = disable$ outputs, $0 = enable$ outputs
19	Q1+	Output	HCSL	Differential true clock output
20	Q1-	Output	HCSL	Differential complementary clock output
22	Q2+	Output	HCSL	Differential true clock output
23	Q2-	Output	HCSL	Differential complementary clock output
24	OE2#	Input	CMOS	Active low input for enabling Q2 pair. This pin has an internal pulldown. $1 = \text{disable outputs}$ , $0 = \text{enable outputs}$
26	OE3#	Input	CMOS	Active low input for enabling Q3 pair. This pin has an internal pulldown. $1 = disable$ outputs, $0 = enable$ outputs
27	Q3+	Output	HCSL	Differential true clock output
28	Q3-	Output	HCSL	Differential complementary clock output
31	VDDA	Power	_	Analog VDD
32	BW_SEL_TRI	Input	Tri-level	Latch to select low-loop bandwidth, bypass PLL, and high-loop bandwidth. This pin has internal pullup resistor
EPAD	EPAD	Power	_	Connect to ground





## **Power Management Table**

PD#	IN	SMBus OE bit	OEn#	Qn+	Qn-	PLL Status
0	X	X	X	Low	Low	Off
1	Running	0	X	Low	Low	On <sup>(1)</sup>
1	Running	1	0	Running	Running	On <sup>(1)</sup>
1	Running	1	1	Low	Low	On <sup>(1)</sup>

Note:

## **PLL Operating Mode Select Table**

PLL_OM	Operating Mode	PLL
0	PLL with Low Bandwidth	Running
M	PLL Bypass	Off
1	PLL with High Bandwidth	Running

<sup>1.</sup> If PLL Bypass mode is selected, the PLL will be off and outputs will be running.





## **Maximum Ratings**

(Above which useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150°C
Supply Voltage to Ground Potential, $V_{DDxx}$ 0.5V to +4.6V
Input Voltage –0.5V to V <sub>DD</sub> +0.5V, not exceed 4.6V
SMBus, Input High Voltage
ESD Protection (HBM)
Junction Temperature125°C max

#### Note:

Stresses greater than those listed under MAXIMUM RAT-INGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

# **Operating Conditions**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DD</sub> , V <sub>DDA</sub> , V <sub>DDR</sub>	Power Supply Voltage	_	3.135	3.3	3.465	V
$I_{DDA}$	Analog Power Supply Current	V <sub>DDA</sub> , PLL mode, All outputs active @ 100MHz	_	21	_	mA
$I_{\mathrm{DD}}$	Power Supply Current	$V_{\rm DD}$ + $V_{\rm DD\_R}$ , All outputs active @ 100MHz	_	70	_	mA
I <sub>DDA_PD</sub>	Analog Power Supply Power Down <sup>(1)</sup> Current	V <sub>DDA</sub> , PLL mode, All outputs LOW/LOW	_	0.6	_	mA
I <sub>DD_PD</sub>	Power Supply Power Down <sup>(1)</sup> Current	V <sub>DD</sub> + V <sub>DD_R</sub> , All outputs LOW/LOW	_	2.5	_	mA
$T_{A}$	Ambient Temperature	Industrial grade	-40	_	85	°C

#### Note:

- 1. Input clock is not running.
- 2. Outputs drive 5 inch trace.

# **Input Electrical Characteristics**

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R <sub>pu</sub>	Internal Pullup Resistance	_	_	120	_	ΚΩ
R <sub>dn</sub>	Internal Pulldown Resistance	_	_	120	_	ΚΩ
L <sub>PIN</sub>	Pin Inductance	_	_	_	7	nН





### **SMBus Electrical Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DDSMB</sub>	Nominal Bus Voltage	_	2.7	_	3.6	V
		SMBus, $V_{DDSMB} = 3.3V$	2.1	_	3.6	
V <sub>IHSMB</sub>	SMBus Input High Voltage	SMBus, V <sub>DDSMB</sub> < 3.3V	0.65 V <sub>DDSMB</sub>	_	_	V
3.7	SMBus Input Low Voltage	SMBus, $V_{DDSMB} = 3.3V$	_	_	0.8	V
V <sub>ILSMB</sub>		SMBus, V <sub>DDSMB</sub> < 3.3V	_	_	0.8	V
I <sub>SMBSINK</sub>	SMBus Sink Current	SMBus, at V <sub>OLSMB</sub>	4	_	_	mA
V <sub>OLSMB</sub>	SMBus Output Low Voltage	SMBus, at I <sub>SMBSINK</sub>	_	_	0.4	V
$f_{MAXSMB}$	SMBus Operating Frequency	Maximum frequency	_	_	500	kHz
t <sub>RMSB</sub>	SMBus Rise Time	(Max $V_{IL}$ - 0.15) to (Min $V_{IH}$ + 0.15)	_	_	1000	ns
t <sub>FMSB</sub>	SMBus Fall Time	(Min $V_{IH}$ + 0.15) to (Max $V_{IL}$ - 0.15)	_	_	300	ns

### **LVCMOS DC Electrical Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
$V_{\mathrm{IH}}$	Input High Voltage	Single-ended inputs, except SMBus	0.75 V <sub>DD</sub>	_	V <sub>DD</sub> +0.3	V
$V_{IM}$	Input Mid Voltage	SADR0_TRI, SADR1_TRI, BW_SEL_TRI	$0.4 V_{ m DD}$	$0.5 \mathrm{V}_\mathrm{DD}$	$0.6 \mathrm{V}_\mathrm{DD}$	V
$V_{\mathrm{IL}}$	Input Low Voltage	Single-ended inputs, except SMBus	-0.3	_	0.25 V <sub>DD</sub>	V
$I_{IH}$	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$	_	_	5	μΑ
$I_{IL}$	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-5	_	_	μΑ
$I_{\mathrm{IH}}$	Input High Current	Single-ended inputs with pullup/pulldown resistor, $V_{\mathrm{IN}} = V_{\mathrm{DD}}$	_	_	50	μΑ
$I_{\mathrm{IL}}$	Input Low Current	Single-ended inputs with pullup/pulldown resistor, $V_{\rm IN}$ = 0V	-50	_	_	μΑ
C <sub>IN</sub>	Input Capacitance	_	1.5	_	5	pF

### **LVCMOS AC Electrical Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
t <sub>OELAT</sub>	Output Enable Latency	Q start after OE# assertion Q stop after OE# deassertion	4	5	10	clocks
t <sub>PDLAT</sub>	PD# Deassertion	Differential outputs enable after PD# deassertion	_	20	300	μs





### **HCSL Input Characteristics(1)**

Temperature = TA; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>IHDIF</sub>	Diff. Input High Voltage <sup>(3)</sup>	IN+, IN-, single-end measurement	600	800	1150	mV
V <sub>ILDIF</sub>	Diff. Input Low Voltage <sup>(3)</sup>	IN+, IN-, single-end measurement	-300	0	300	mV
V <sub>COM</sub>	Diff. Input Common Mode Voltage		150	_	900	mV
V <sub>SWING</sub>	Diff. Input Swing Voltage	Peak to peak value (V <sub>IHDIF</sub> - V <sub>ILDIF)</sub>	300	_	2900	mV
f <sub>INBP</sub>	Input Frequency	PLL Bypass mode	1	_	400	MHz
f <sub>IN100</sub>	Input Frequency	100MHz PLL	98.5	100	102.5	MHz
f <sub>MODI</sub> - PCIe	Input SS Modulation Freq. PCIe	Allowable frequency for PCIe applications (Triangular Modulation)	30	_	33	kHz
t <sub>STAB</sub>	Clock stabilization	From $V_{DD}$ Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock	_	0.75	1.0	ms
t <sub>RF</sub>	Diff. Input Slew Rate <sup>(2)</sup>	Measured differentially	0.4	_	_	V/ns
I <sub>IN</sub>	Diff. Input Leakage Current	$V_{IN} = V_{DD}, V_{IN} = GND$	-5	0.01	5	uA
$t_{DC}$	Diff. Input Duty Cycle	Measured differentially	45		55	%
tj <sub>c-c</sub>	Diff. Input Cycle to cycle jitter	Measured differentially	_	_	125	ps

#### Note:

- 1. Guaranteed by design and characterization, not 100% tested in production
- 2. Slew rate measured through +/-75mV window centered around differential zero
- 3. The device can be driven by a single-ended clock by driving the true clock and biasing the complement clock input to the Vbias, where Vbias is (V<sub>IH</sub>-V<sub>IL</sub>)/2

## **HCSL Output DC Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V <sub>OH</sub>	Output Voltage High <sup>(1)</sup>	Statistical measurement on single-ended	660	_	850	mV
V <sub>OL</sub>	Output Voltage Low <sup>(1)</sup>	signal using oscilloscope math function	-150	_	150	mV
V <sub>OMAX</sub>	Output Voltage Maximum <sup>(1)</sup>	Measurement on single ended signal using	_	_	1150	mV
V <sub>OMIN</sub>	Output Voltage Minimum <sup>(1)</sup>	absolute value	-300	_	_	mV
V <sub>OC</sub>	Output Cross Voltage(1,2,4)	_	250	_	550	mV
DV <sub>OC</sub>	V <sub>OC</sub> Magnitude Change <sup>(1,2,5)</sup>	_	_	_	140	mV

- $1. \ At \ default \ SMBUS \ amplitude \ settings.$
- 2. Guaranteed by design and characterization—not 100% tested in production.
- 3. Measured from differential waveform.
- 4. This one is defined as voltage where Q + = Q- measured on a component test board and only applied to the differential rising edge.
- 5. The total variation of all Vcross measurements in any particular system. This is a subset of Vcross\_min/max allowed.





# **HCSL Output AC Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
C	0.4.45	PLL mode	_	100	_	MHz
$f_{OUT}$	Output Frequency	PLL bypass mode	_	_	400	MHz
DIAZ	PLL Bandwidth <sup>(1,8)</sup>	-3dB point in High Bandwidth Mode	_	_	4	MHz
BW	PLL Bandwidtn(+)**	-3dB point in Low Bandwidth Mode	_	_	1.4	MHz
	DILI'' D 1:	Peak pass band gain, low bandwidth	_	_	2	dB
tj <sub>peak</sub>	PLL Jitter Peaking	Peak pass band gain, high bandwidth	_	_	2.5	dB
t <sub>RF</sub>	Slew Rate <sup>(1,2,3)</sup>	Scope averaging on fast setting	2	_	4.0	V/ns
Dt <sub>RF</sub>	Slew Rate Matching <sup>(1,2,4)</sup>	Scope averaging on	_	_	20	%
t <sub>SKEW</sub>	Output Skew <sup>(1,2)</sup>	Averaging on, $V_T = 50\%$	_	_	50	ps
		PLL Bypass mode, $V_T$ = 50%, across temperature and VDD	2000	_	3000	ps
		PLL Bypass mode, $V_T = 50\%$ , norminal temperature and VDD	_	_	2500	ps
tpdelay	Propagation Delay	PLL mode, $V_T$ = 50%, norminal temperature and VDD	_	_	50	ps
		PLL mode, $V_T$ = 50%, across temperature and VDD	_	_	100	ps
$t_{\rm DC}$	Duty Cycle <sup>(1,2)</sup>	Measured differentially, PLL Mode	45	50	55	%
$t_{\rm DCD}$	Duty Cycle Distortion <sup>(1,7)</sup>	Measured differentially, PLL Bypass Mode at 100MHz	-3.5	0	3.5	%
	0.1. 0.1. 7. (12)	PLL mode	_	14	_	ps
tj <sub>c-c</sub>	Cycle-to-Cycle Jitter <sup>(1,2)</sup>	Additive jitter, Bypass mode	_	0.1	_	ps





# **HCSL Output AC Characteristics (PLL Mode PCIe Phase Jitter)**

Symbol	Parameters	Condition	Min.	Тур.	Max.	Spec Limit	Units
		PCIe 1.0 <sup>(6)</sup>	_	2.6	_	86	ps (p-p)
		PCIe 2.0 Low Band, 10kHz < f < 1.5MHz	_	0.08	_	3.1	ps
	Integrated Phase Jitter PLL Mode (RMS) <sup>(1,5)</sup>	PCIe 2.0 High Band, 1.5MHz < f < Nyquist (50MHz)	_	0.09	_	3	ps
tjpH_PLL_ CC	Low Bandwidth (Common Clocked Architecture)	PCIe 3.0 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	_	0.05	_	1	ps
	Clocked Membertare)	PCIe 4.0 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	_	0.05	_	0.5	ps
		PCIe 5.0 <sup>(11)</sup> (PLL BW of 500k to 1.8MHz. CDR =20MHz)	_	0.018	_	0.15	ps
	Integrated Phase Jitter PLL Mode (RMS) <sup>(1,5)</sup> Low Bandwidth (SRIS Architecture)	PCIe 1.0	_	8.71	_	_	ps (p-p)
		PCIe 2.0	_	0.81	_	_	ps
tj <sub>PH_PLL_</sub> SRIS		PCIe 3.0	_	0.329	_	_	ps
3K13		PCIe 4.0	_	0.222	_	_	ps
		PCIe 5.0 <sup>(11)</sup>	_	0.084	_	_	ps
		PCIe 1.0 <sup>(6)</sup>	_	5.4	_	86	ps (p-p)
		PCIe 2.0 Low Band, 10kHz < f < 1.5MHz	_	0.09	_	3.1	ps
	Integrated Phase Jitter PLL Mode (RMS) <sup>(1,5)</sup>	PCIe 2.0 High Band, 1.5MHz < f < Nyquist (50MHz)	_	0.019	_	3	ps
tjpH_PLL_ CC	High Bandwidth (Common Clocked Architecture)	PCIe 3.0 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	_	0.1	_	1	ps
		PCIe 4.0 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)		0.1	_	0.5	ps
		PCIe 5.0 <sup>(11)</sup> (PLL BW of 500k to 1.8MHz. CDR =20MHz)	_	0.032	_	0.15	ps





### HCSL Output AC Characteristics (PLL Mode PCIe Phase Jitter) Cont.

Symbol	Parameters	Condition	Min.	Тур.	Max.	Spec Limit	Units
		PCIe 1.0	_	8.61	_	_	ps (p-p)
	Integrated Phase Jitter PLL	PCIe 2.0	_	0.88	_	_	ps
tj <sub>PH_PLL_</sub> SRIS	Mode (RMS) <sup>(1,5)</sup> High Bandwidth (SRIS	PCIe 3.0	_	0.354	_	_	ps
SKIS	Architecture)	PCIe 4.0	_	0.271	_	_	ps
		PCIe 5.0 <sup>(11)</sup>	_	0.097	_	_	ps

- 1. Guaranteed by design and characterization—not 100% tested in production.
- 2. Measured from differential waveform.
- $3. \ Slew\ rate\ is\ measured\ through\ the\ Vswing\ voltage\ range\ centered\ around\ differential\ 0V,\ within\ \pm 150mV\ window.$
- 4. Slew rate matching is measured through ±75mV window centered around differential zero.
- 5. See http://www.pcisig.com for complete specs.
- 6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of  $10^{-12}$ .
- 7. Duty cycle distortion is the difference in duty cycle between the output and input clock when the device is operated in the PLL bypass mode.
- 8. The Min and Max values of each BW setting track each other, low BW max will never occur with high BW min.
- 9. Applies to all differential outputs.
- 10. For additive jitter RMS value is calculated by the following equation = SQRT [(total jitter)\*2 (input jitter)\*2].
- 11. PCIe 5.0 v0.9 specification.





## **HCSL Output AC Characteristics (Fanout Buffer Mode Additive Phase Jitter)**

Symbol	Parameters	Condition	Min.	Тур.	Max.	Spec Limit	Units
		PCIe 1.0 <sup>(6)</sup>	_	1.3	_	86	ps (p-p)
		PCIe 2.0 Low Band, 10kHz < f < 1.5MHz	_	0.023	_	3.1	ps
	Additive Integrated Phase Jitter (RMS) <sup>(1,5)</sup>	PCIe 2.0 High Band, 1.5MHz < f < Nyquist (50MHz)	_	0.089	_	3	ps
tjpH_A_CC	(Common Clocked Architecture)	PCIe 3.0 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	_	0.044	_	1	ps
	tecture)	PCIe 4.0 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	_	0.044	_	0.5	ps
		PCIe 5.0 <sup>(11)</sup> (PLL BW of 500k to 1.8MHz. CDR =20MHz)	_	0.017	_	0.15	ps
		PCIe 1.0	_	0.127	_	_	ps (p-p)
	Additive Integrated Phase	PCIe 2.0	_	0.112	_	_	ps
tj <sub>PH_A_SRIS</sub>	Jitter (RMS) <sup>(1,5,10)</sup>	PCIe 3.0	_	0.029	_	_	ps
	(SRIS Architecture)	PCIe 4.0	_	0.031	_	_	ps
		PCIe 5.0 <sup>(11)</sup>	_	0.027	_	_	ps
tj <sub>PH_A_12k</sub> -	Additive Integrated Phase Jitter (RMS) <sup>(1,5,10)</sup>	133.33MHz	_	150	_	_	fs
20M	12kHz ~ 20MHz	100MHz, SSC off	_	90	_	_	fs

- 1. Guaranteed by design and characterization—not 100% tested in production.
- 2. Measured from differential waveform.
- 3. Slew rate is measured through the Vswing voltage range centered around differential 0V, within ±150mV window.
- 4. Slew rate matching is measured through ±75mV window centered around differential zero.
- 5. See http://www.pcisig.com for complete specs.
- 6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of  $10^{-12}$ .
- 7. Duty cycle distortion is the difference in duty cycle between the output and input clock when the device is operated in the PLL bypass mode.
- 8. The Min and Max values of each BW setting track each other, low BW max will never occur with high BW min.
- 9. Applies to all differential outputs.
- 10. For additive jitter RMS value is calculated by the following equation = SQRT [(total jitter)\*2 (input jitter)\*2].
- 11. PCIe 5.0 v0.9 specification.





# **HCSL Output AC Characteristics (Jitter)**

Symbol	Parameters	Condition	Min.	Тур.	Max.	Spec Limit	Units
		QPI and UPI, 100M or 133.33MHz, 4.8Gbps, 6.4Gbps 12UI	_	0.16	_	0.5	ps
tj <sub>PHPLL</sub> QPI_UPI	Integrated Phase Jitter PLL Mode (RMS) <sup>(1,5)</sup>	QPI and UPI, 100MHz, 8.0Gbps, 12UI	_	0.1	_	0.3	ps
QPI_UPI	Mode (KM)	QPI and UPI, 100MHz, <11.4Gbps, 12UI	_	0.08	_	0.2	ps
	Fanout Buffer Mode	QPI and UPI, 100M or 133.33MHz, 4.8Gbps, 6.4Gbps 12UI	_	0.03	_	_	ps (p-p)
tj <sub>PH_QPI_</sub> UPI	Additive Integrated Phase	QPI and UPI, 100MHz, 8.0Gbps, 12UI	_	0.03	_	_	ps
UPI	Jitter (RMS) <sup>(1,5,10)</sup>	QPI and UPI, 100MHz, <11.4Gbps, 12UI	_	0.02	_	_	ps
	PLL Mode IF-UPI phase	Low bandwidth	_	0.1	_	_	ps
tj <sub>PH_IFUPI</sub>	jitter	High bandwidth	_	0.17	_	_	ps
GPH_IFOPI	Fanout Buffer Mode IF- UPI phase jitter		_	0.06	_	_	ps
tj <sub>PH</sub> _ DB2000Q	Fanout Buffer Mode DB2000Q phase jitter		_	28	_	_	fs

- 1. Guaranteed by design and characterization—not 100% tested in production.
- 2. Measured from differential waveform.
- 3. Slew rate is measured through the Vswing voltage range centered around differential 0V, within  $\pm 150 \text{mV}$  window.
- 4. Slew rate matching is measured through ±75mV window centered around differential zero.
- 5. See http://www.pcisig.com for complete specs.
- 6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of 10<sup>-12</sup>.
- 7. Duty cycle distortion is the difference in duty cycle between the output and input clock when the device is operated in the PLL bypass mode.
- 8. The Min and Max values of each BW setting track each other, low BW max will never occur with high BW min.
- 9. Applies to all differential outputs.
- 10. For additive jitter RMS value is calculated by the following equation = SQRT [(total jitter) $^{*2}$  (input jitter) $^{*2}$ ].
- 11. PCIe 5.0 v0.9 specification.





### **SMBus Serial Data Interface**

PI6CBE33045 is a slave-only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

**Address Assignment** 

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	See SMBus Ad	dress Selection t	able	1/0

Note: SMBus address is latched on SADR pin

### **SMBus Address**

I	Pin		SMBus	Address	
SADR1_tri	SADR0_tri	PI6CBE3312x	PI6CBE3308x	PI6CBE3306x	PI6CBE33045
0	0	D8	D8	D8	D8
0	M	DA	N/A	N/A	DA
0	1	DE	N/A	N/A	DE
M	0	C2	N/A	N/A	N/A
M	M	C4	N/A	N/A	N/A
M	1	C6	N/A	N/A	N/A
1	0	CA	N/A	N/A	N/A
1	M	CC	N/A	N/A	N/A
1	1	CE	N/A	N/A	N/A

Note: PI6CBE3308x and PI6CBE3306x do not have SMBus address select pins. Their address is D8.

#### **How to Write**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

#### **How to Read**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

8 bits	1 bit	1 bit
Data Byte	NAck	Stop bit
(N+X-1)	INACK	Stop bit





# Byte 0: PLL Operating Mode and Frequency Select Register

Bit	<b>Control Function</b>	Description	Туре	Power-up Condition	0	1
7	PLLMODERB1	PLL Mode Readback Bit1	R	Latch	00 = Low BW	ZDB
					01= Fanout me	ode
6	PLLMODERB0	PLL Mode Readback Bit0	R	Latch	10 = Reserved	
					11 = High BW	ZDB
5	Reserved	_		0	_	_
4	Reserved	_		0	_	_
3	PLL SW Control	PLL Mode control Bit0	RW <sup>(1)</sup>	0	Hardware Latch	SMBus Control
2	PLL mode	PLL Mode 1	RW	1	00 = Low BW	ZDB
					01= Fanout me	ode
1	PLL mode	PLL Mode 0	RW	1	10 = Reserved	
					11 = High BW	ZDB
0	Frequency Select RB	Frequency select readback	R	Latch	133MHz	100MHz

# Byte 1: Output Enable Register 1

Bit	<b>Control Function</b>	Description	Туре	Power-up Condition	0	1
7	Reserved		RW	0		
6	Q2_OE	Q2 output enable	RW	1	Output Low/ Low	OE Pin Control
5	Q1_OE	Q1 output enable	RW	1	Output Low/ Low	OE Pin Control
4	Reserved	_	RW	0	_	_
3	Reserved	_	RW	0	_	_
2	Q0_OE	Q0 output enable	RW	1	Output Low/ Low	OE Pin Control
1	Reserved	_	RW	0	_	_
0	Reserved	_	RW	0	_	_

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## Byte 2: Output Enable Register 2

Bit	Control Function	Description	Туре	Power-up Condition	0	1
7	Reserved	_	RW	0	_	_
6	Reserved	_	RW	0	_	_
5	Reserved	_	RW	0	_	_
4	Reserved	_	RW	0	_	_
3	Reserved	_	RW	0	_	_
2	Reserved	_	RW	0	_	_
1	Q3_OE	Q3 output enable	RW	1	Output Low/ Low	OE Pin Control
0	Reserved	_	RW	0	_	_

# Byte 3 and Byte 4: Reserved

# Byte 5: Revision and Vendor ID Register

Bit	Control Function	Description	Туре	Power-up Condition	0	1	
7	RID3		R	0			
6	RID2	Project ID	R	0	0000		
5	RID1	Revision ID	R	0	rev = 0000		
4	RID0		R	0			
3	PVID3		R	0			
2	PVID2	W 1 ID	R	0	D: 1 0011		
1	PVID1	Vendor ID	R	1	Diodes = 0011		
0	PVID0		R	1			

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# **Byte 6: Device ID Register**

Bit	Control Function	Description	Туре	Power-up Condition
7	- NA	DID7	R	
6		DID6	R	
5		DID5	R	
4		DID4	R	ol Di
3		DID3	R	0hB1
2		DID2	R	
1		DID1	R	
0		DID0	R	

# **Byte 7: Byte Count Register**

Bit	Control Function	Description	Type	Power-up Condition	0	1
7	Reserved	_		0	_	_
6	Reserved	_		0	_	_
5	Reserved	_		0	_	_
4	BC4		RW	0	_	_
3	BC3		RW	1	_	_
2	BC2	Wring to the register configures how many bytes will be read back on a block read	RW	0	_	_
1	BC1		RW	0	_	_
0	BC0		RW	0	_	_





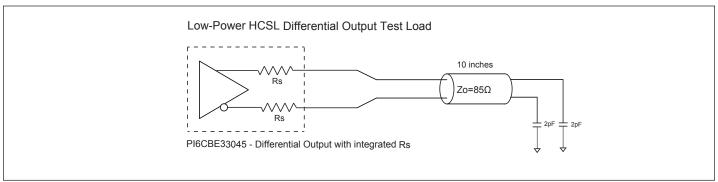


Figure 1. Low-Power HCSL Test Circuit

### **Test Loads**

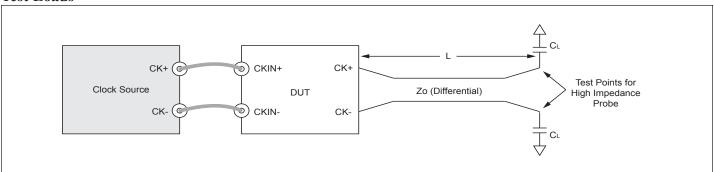


Figure 2. Test Load for AC/DC Measurements

### **AC/DC** Measurements Table

Clock Source	Device Under Test (DUT)	Rs (Ω)	Differential Zo ( $\Omega$ )	L (cm)	C <sub>L</sub> (pF)
SMA100B	PI6CBE33xx5	Internal	85	25.4	2

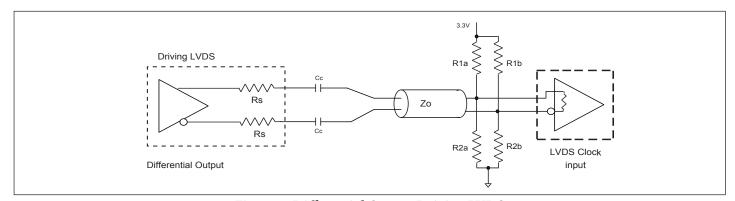


Figure 3. Differential Output Driving LVDS





## Alternate Differential Output Terminations ( $Z_O = 85\Omega$ )

Component	Receiver with Termination	Receiver without Termination	Unit
R <sub>1a</sub> , R <sub>1b</sub>	10,000	130	Ω
$R_{2a}, R_{2b}$	5600	64	Ω
C <sub>C</sub>	0.1	0.1	μF
$V_{CM}$	1.2	1.2	V

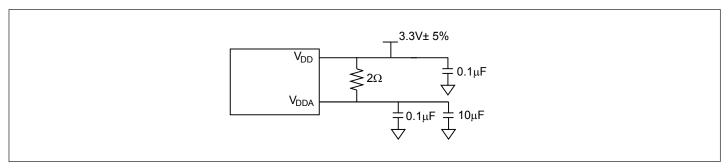
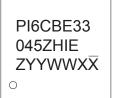


Figure 4. Power Supply Filter

### **Thermal Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit		
$\theta_{\mathrm{JA}}$	Thermal Resistance Junction to Ambient	Still air				°C/W		
$\theta_{ m JC}$	Thermal Resistance Junction to Case					°C/W		

# **Part Marking**



Z: Die Rev

YY: Date Code (Year)

WW: Date Code (Workweek) 1st X: Assembly Site Code

2nd X: Wafer Fab Site Code

Bar above Fab Code means Cu Wire

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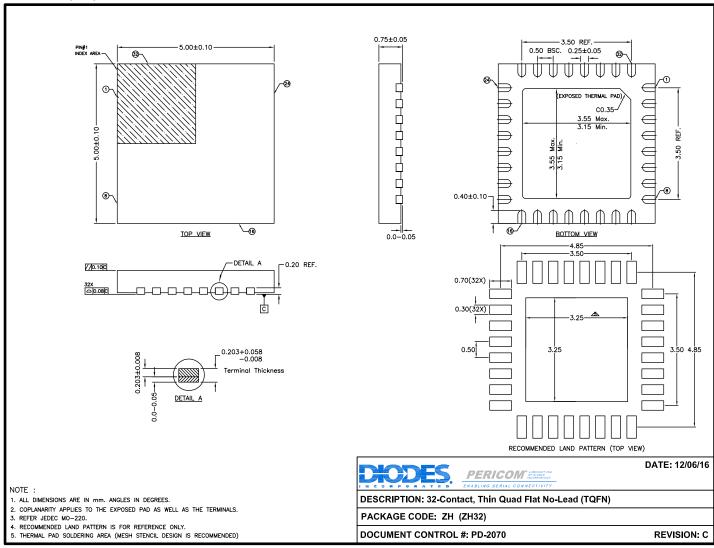
June 2022





# **Packaging Mechanical**

### **32-TQFN (ZH)**



17-0570

#### For latest package information:

See http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/.





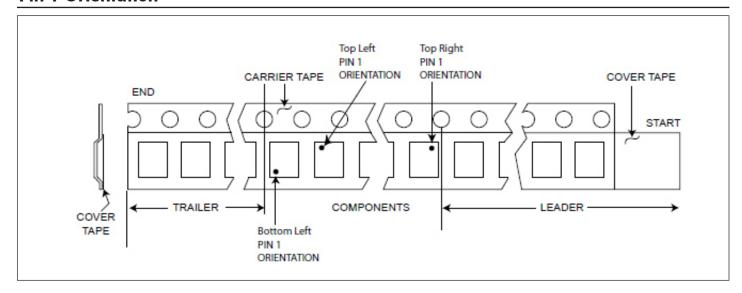
## **Ordering Information**

Ordering Code	Package Code	Package Description	Temperature	Pin 1 Orientation
PI6CBE33045ZHIEX	ZH	32-Contact, Thin Quad Flat No-Lead (TQFN)	-40~85°C	Top Right Corner
PI6CBE33045ZHIEX-13R	ZH	32-Contact, Thin Quad Flat No-Lead (TQFN)	-40~85°C	Top Left Corner

#### Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- $2. \ See \ https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.$
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. I = Industrial
- 5. E = Pb-free and Green
- 6. X suffix = Tape/Reel
- 7. For packaging detail, go to our website at: https://www.diodes.com/assets/MediaList-Attachments/Diodes-Package-Information.pdf

### **Pin 1 Orientation**







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